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Question Paper Code: R4809

B.E. / B.Tech. DEGREE EXAMINATION, NOV 2025

Professional Elective

Electronics and Communication Engineering

R21ECV509 - CMOS ADVANCED MICRO FABRICATION USING SEMULATOR 3D

(Regulations R2021)

Duration: Three hours

Maximum: 100 Marks

Answer ALL Questions

PART A - (10 x 2 = 20 Marks)

1. Explain NMOS and PMOS transistors. CO1-U
2. Interpret the design rules in CMOS layout. CO1-U
3. Differentiate between LOCOS and STI. CO1-U
4. Explain about gate dielectric. Give an examples. CO1-U
5. Explain about reactive ion etching (RIE). CO1-U
6. Summarize about a mask aligner to copy a circuit pattern onto a silicon wafer during photolithography. CO1-U
7. Distinguish between PVD and CVD. CO1-U
8. Illustrate about ALD. Where is it used? CO1-U
9. Illustrate the various fabrication steps (like doping, deposition, and lithography) to ensure proper functioning and yield of a CMOS device CO1-U
10. Summarize any one reliability challenge in advanced CMOS. CO1-U

PART – B (5 x 16= 80 Marks)

11. (a) Explain the CMOS fabrication process with neat diagrams. CO1 U (16)
Or
(b) Explain the purpose of design rules in IC layout. How do these rules help in avoiding manufacturing defects during fabrication? CO1 U (16)
12. (a) Discuss the advantages of using high-k/metal gate over traditional gate materials. CO1-U (16)
Or
(b) Explain the challenges in integrating Hi-K materials in nanoscale CMOS. CO1-U (16)

13. (a) Explain the lithography process in IC fabrication. CO1-U (16)
Or
(b) Explain how multiple patterning overcomes the limitations of traditional lithography. CO1-U (16)
14. (a) What is annealing? Describe its role in activation. CO1-U (16)
Or
(b) With neat diagrams, describe the process of Physical Vapor Deposition (PVD). List different PVD techniques and their applications. CO1-U (16)
15. (a) Apply the concept of electromigration and explain how it influences interconnect design and material choice in sub-10nm technology nodes. CO3-App (16)
Or
(b) Elucidate how dual damascene processing is applied in multilayer interconnects. What makes it preferable over traditional subtractive etching methods? CO3-App (16)